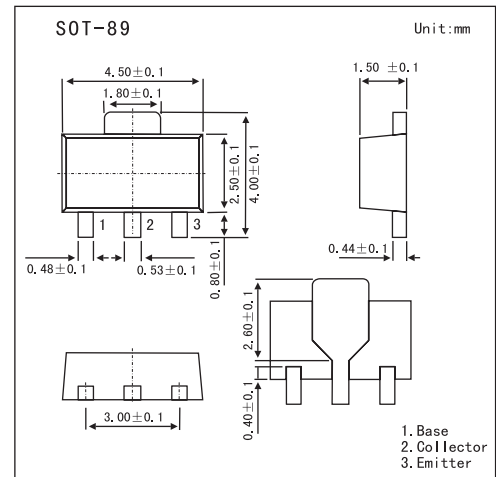


## NPN Epitaxial Planar Silicon Transistor

## 2SC4390

## ■ Features

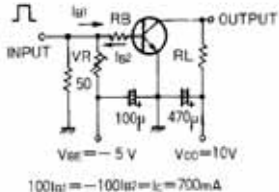
- Adoption of MBIT process.
- High DC current gain ( $h_{FE}=800$  to  $3200$ ).
- Large current capacity ( $I_C=2A$ ).
- Low collector-to-emitter saturation voltage ( $V_{CE(sat)} \leq 0.3V$ ).
- High  $V_{EBO}$  ( $V_{EBO} \geq 15V$ ).

■ Absolute Maximum Ratings  $T_a = 25^\circ C$ 

Parameter	Symbol	Rating	Unit
Collector-base voltage	$V_{CBO}$	20	V
Collector-emitter voltage	$V_{CEO}$	10	V
Emitter-base voltage	$V_{EBO}$	15	V
Collector current	$I_C$	2	A
Collector current (pulse)	$I_{CP}$	4	A
Base current	$I_B$	0.4	A
Collector dissipation	$P_C$	500	mW
Junction temperature	$T_j$	150	$^\circ C$
Storage temperature	$T_{stg}$	-55 to +150	$^\circ C$

## 2SC4390

## ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Collector cutoff current	ICBO	V <sub>CB</sub> = 15V, I <sub>E</sub> =0			0.1	μA
Emitter cutoff current	IEBO	V <sub>EB</sub> = 10V, I <sub>C</sub> =0			0.1	μA
DC current gain	hFE	V <sub>CE</sub> = 2V, I <sub>C</sub> = 500mA	800	1500	3200	
Gain bandwidth product	f <sub>T</sub>	V <sub>CE</sub> = 10V, I <sub>C</sub> = 50mA		260		MHz
Output capacitance	C <sub>ob</sub>	V <sub>CB</sub> = 10V, f = 1.0MHz		280		pF
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	I <sub>C</sub> = 1 A, I <sub>B</sub> = 20mA		0.11	0.5	V
Base-emitter saturation voltage	V <sub>BE(sat)</sub>	I <sub>C</sub> = 1 A, I <sub>B</sub> = 20mA		0.87	1.2	V
Collector-base breakdown voltage	V <sub>(BR)CBO</sub>	I <sub>C</sub> = 10μA, I <sub>E</sub> = 0	20			V
Collector-emitter breakdown voltage	V <sub>(BR)CEO</sub>	I <sub>C</sub> = 1mA, R <sub>BE</sub> = ∞	10			V
Emitter-base breakdown voltage	V <sub>(BR)EBO</sub>	I <sub>E</sub> = 10μA, I <sub>C</sub> = 0	15			V
Turn-on time	t <sub>on</sub>	<b>Switching Time Test Circuit</b> PW = 20μs DC ≤ 1% 	0.13		μs	
Storage time	t <sub>stg</sub>		0.8		μs	
Fall time	t <sub>f</sub>		0.1		μs	